

BULD118D-1

HIGH VOLTAGE FAST-SWITCHING NPN POWER TRANSISTOR

- INTEGRATED ANTIPARALLEL COLLECTOR- EMITTER DIODE
- HIGH VOLTAGE CAPABILITY
- LOW SPREAD OF DYNAMIC PARAMETERS
- MINIMUM LOT-TO-LOT SPREAD FOR RELIABLE OPERATION
- VERY HIGH SWITCHING SPEED

APPLICATIONS:

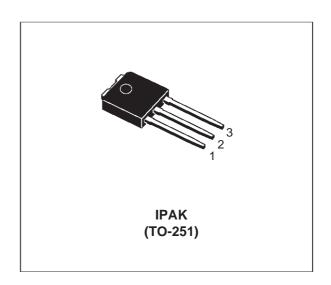
- ELECTRONIC BALLASTS FOR FLUORESCENT LIGHTING
- FLYBACK AND FORWARD SINGLE TRANSISTOR LOW POWER CONVERTERS

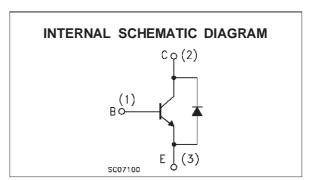
DESCRIPTION

The device is manufactured using high voltage Multi Epitaxial Planar technology for high switching speeds and medium voltage capability.

It uses a Cellular Emitter structure with planar edge termination to enhance switching speeds while maintaining the wide RBSOA.

The device is designed for use in lighting applications and low cost switch-mode power supplies.





ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{CES}	Collector-Emitter Voltage (V _{BE} = 0)	700	V
Vceo	Collector-Emitter Voltage (I _B = 0)	400	V
V_{EBO}	Emitter-Base Voltage ($I_C = 0$)	9	V
Ic	Collector Current	2	Α
I _{CM}	Collector Peak Current (tp < 5 ms)	4	Α
lΒ	Base Current	1	Α
I _{BM}	Base Peak Current (t _p < 5 ms)	2	Α
P _{tot}	Total Dissipation at T _c = 25 °C	20	W
T _{stg}	Storage Temperature	-65 to 150	°C
Tj	Max. Operating Junction Temperature	150	°C

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THERMAL DATA

R _{thj}	-case Th	ermal	Resistance	Junction-Case	Max	6.25	°C/W
R _{thj} .	- _{amb} Th	ermal	Resistance	Junction-Ambient	Max	100	°C/W

ELECTRICAL CHARACTERISTICS ($T_{case} = 25$ °C unless otherwise specified)

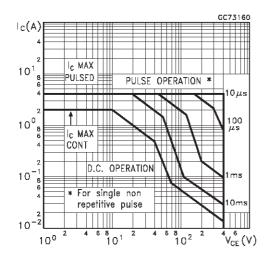
Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
I _{CES}	Collector Cut-off Current (V _{BE} = 0)	V _{CE} = 700 V V _{CE} = 700 V	T _j = 125 °C			100 500	μA μA
V _{EBO}	Emitter-Base Voltage	I _E = 10 mA		9			V
V _{CEO(sus)}	Collector-Emitter Sustaining Voltage	I _C = 100 mA	L = 25 mH	400			V
I _{CEO}	Collector-Emitter Leakage Current	V _{CE} = 400 V				250	μА
V _{CE(sat)} *	Collector-Emitter Saturation Voltage	I _C = 0.5 A I _C = 1 A I _C = 2 A	$I_B = 0.1 A$ $I_B = 0.2 A$ $I_B = 0.4 A$			0.5 1 1.5	V V V
V _{BE(sat)*}	Base-Emitter Saturation Voltage	I _C = 0.5 A I _C = 1 A I _C = 2 A	I _B = 0.1 A I _B = 0.2 A I _B = 0.4 A			1.0 1.2 1.3	V V V
h _{FE} *	DC Current Gain	I _C = 10 mA I _C = 0.5 A I _C = 2 A	V _{CE} = 5 V V _{CE} = 5 V V _{CE} = 5 V	10 10 8		50	
t _r t _f t _s	RESISTIVE LOAD Rise Time Fall Time Storage Time group A group B	$VCC = 125 V$ $I_{B1} = 0.4 A$ $t_p = 30 \mu s$	I _C = 2 A I _{B2} = -0.2 A	1.4	0.7 0.3	0.5 2.1 2.75	μs μs μs μs
ts t _f	INDUCTIVE LOAD Storage Time Fall Time	I _C = 1 A V _{BE} = -5 V V _{clamp} = 300 V	I _{B1} = 0.2 A L = 50 mH		0.8 0.10		μs μs
V_{F}	Diode Forward Voltage	IC = 1 A				2.5	V

* Pulsed: Pulse duration = 300 µs, duty cycle 1.5 %

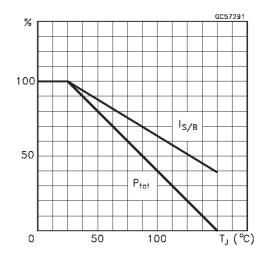
Note: Product is pre-selected in storage time (GROUP A and GROUP B). SGS-THOMSON reserves the right to ship either groups according to production availability. Please contact your nearest SGS THOMSON MICROELECTRONICS sales office for delivery details.

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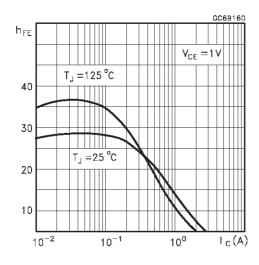
Safe Operating Areas



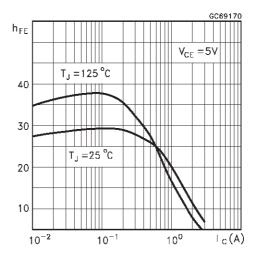
Derating Curve



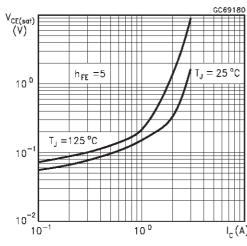
DC Current Gain



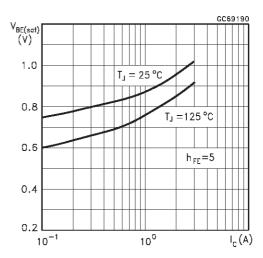
DC Current Gain



Collector Emitter Saturation Voltage

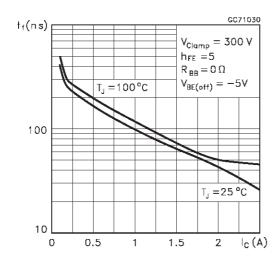


Base Emitter Saturation Voltage

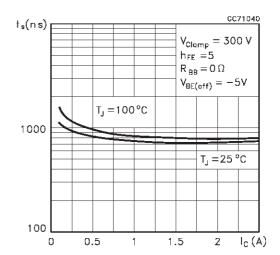


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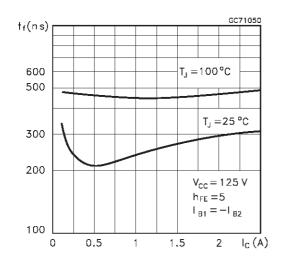
Inductive Fall Time



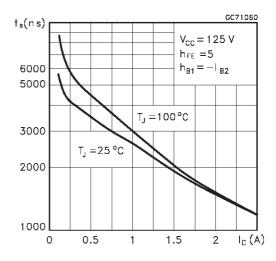
Inductive Storage Time



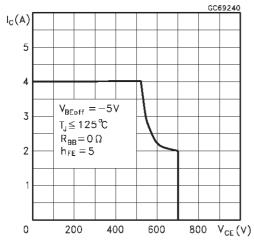
Resistive Fall Time



Resistive Load Storage Time



Reverse Biased SOA



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Figure 1: Inductive Load Switching Test Circuit.

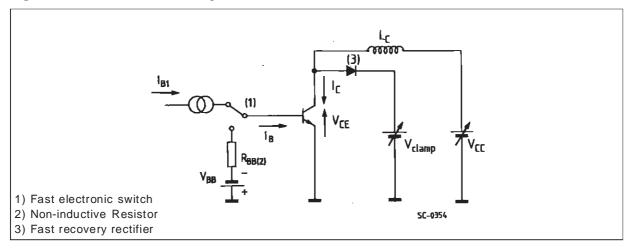
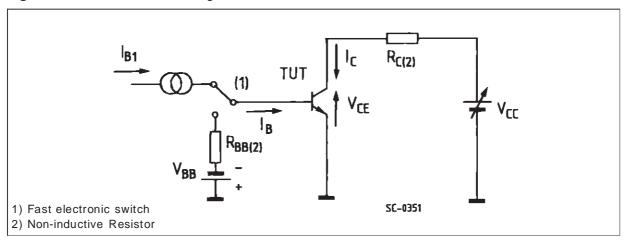
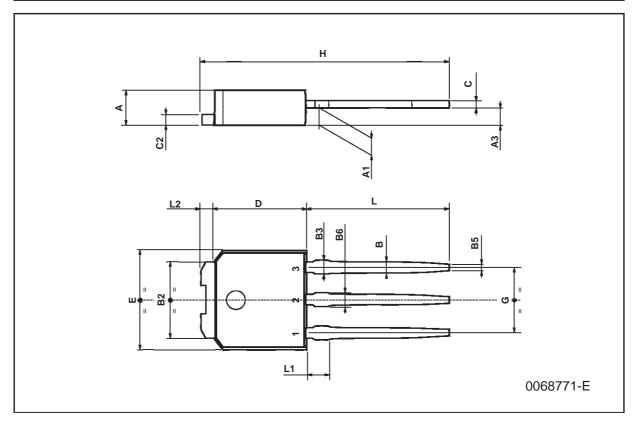


Figure 2: Resistive Load Switching Test Circuit.



TO-251 (IPAK) MECHANICAL DATA

DIM.		mm		inch			
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
А	2.2		2.4	0.086		0.094	
A1	0.9		1.1	0.035		0.043	
А3	0.7		1.3	0.027		0.051	
В	0.64		0.9	0.025		0.031	
B2	5.2		5.4	0.204		0.212	
В3			0.85			0.033	
B5		0.3			0.012		
B6			0.95			0.037	
С	0.45		0.6	0.017		0.023	
C2	0.48		0.6	0.019		0.023	
D	6		6.2	0.236		0.244	
Е	6.4		6.6	0.252		0.260	
G	4.4		4.6	0.173		0.181	
Н	15.9		16.3	0.626		0.641	
L	9		9.4	0.354		0.370	
L1	0.8		1.2	0.031		0.047	
L2		0.8	1		0.031	0.039	



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